

# D8555N

**100%  $\Delta V_{ds}$  TESTED!**

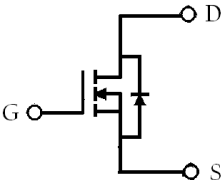
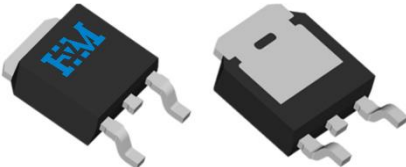
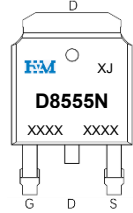
**100% UIS TESTED!**

$BV_{DSS}$	<b>30</b>	V	
$I_D@V_{GS}=10V, T_C=25^\circ C$	<b>85</b>	A	
$R_{DSON}, T_C=25^\circ C$	Typ	Max	
@ $V_{GS}=10V, I_D=30A$	<b>4.5</b>	<b>5.5</b>	m $\Omega$
@ $V_{GS}=4.5V, I_D=20A$	<b>5.5</b>	<b>7.0</b>	

## Features

- Super Low Gate Charge
- Green Device Available
- Excellent  $CdV/dt$  effect decline
- Advanced Trench technology



Equivalent Circuit	TO-252	Marking & Pin Assignment
		

## Package Marking and Ordering Information

Device Name	Marking	Device Package	Quantity
HMD8555N	D8555N	TO-252	2500/Reel

**Table 1. Absolute Maximum Ratings (TA=25°C)**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-Source Voltage ( $V_{GS}=0V$ )	30	V
$V_{GS}$	Gate-Source Voltage ( $V_{DS}=0V$ )	$\pm 20$	V
$I_{D(DC)}$	Drain Current-Continuous ( $T_C=25^\circ C$ ) <sup>1</sup>	85	A
	Drain Current-Continuous ( $T_C=100^\circ C$ ) <sup>1</sup>	58.5	A
$I_{DM(pulse)}$	Drain Current-Continuous@ Current-Pulsed <sup>2</sup>	340	A
$P_D$	Maximum Power Dissipation ( $T_C=25^\circ C$ ) <sup>4</sup>	81	W
$E_{AS}$	Single Pulse Avalanche Energy <sup>3</sup>	225	mJ
$T_J, T_{STG}$	Operating Junction and Storage Temperature Range	-55 To 150	°C

**Table 2. Thermal Characteristic**

Symbol	Parameter	Max	Unit
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	1.85	°C/W



**Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>On/Off States</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current(Tc=25°C)	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1	μA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.5	2.5	V
R <sub>DS(ON)</sub>	Drain-Source On-State Resistance <sup>2</sup>	V <sub>GS</sub> =10V, I <sub>D</sub> =30A		4.5	5.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A		5.5	7.0	mΩ
<b>Dynamic Characteristics</b>						
R <sub>G</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V f=1.0MHz		2.0		Ω
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V f=1.0MHz		2230		PF
C <sub>oss</sub>	Output Capacitance			300		PF
C <sub>rss</sub>	Reverse Transfer Capacitance			275		PF
<b>Switching Times</b>						
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>D</sub> =20A, R <sub>G</sub> =2.0Ω		7.0		nS
t <sub>r</sub>	Turn-on Rise Time			14.0		nS
t <sub>d(off)</sub>	Turn-Off Delay Time			35.0		nS
t <sub>f</sub>	Turn-Off Fall Time			12.0		nS
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>D</sub> =20A		42.5		nC
Q <sub>gs</sub>	Gate-Source Charge			7.0		nC
Q <sub>gd</sub>	Gate-Drain Charge			12.0		nC
<b>Source-Drain Diode Characteristics</b>						
I <sub>SD</sub>	Source-Drain Current (Body Diode) <sup>1.5</sup>				85	A
V <sub>SD</sub>	Forward On Voltage <sup>2</sup>	I <sub>SD</sub> =20A, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	T <sub>J</sub> =25°C I <sub>F</sub> =20A, di/dt=100A/μs		14		nS
Q <sub>rr</sub>	Reverse Recovery Charge			5		nC
t <sub>on</sub>	Forward Turn-on Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS +LD)				

**Notes:**

- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
3. The test condition is V<sub>DD</sub> =20V, V<sub>GS</sub> =10V, L=0.5mH, I<sub>AS</sub>=30A.
- 4.The power dissipation is limited by 175°C junction temperature.
- 5.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.



## Typical Characteristics

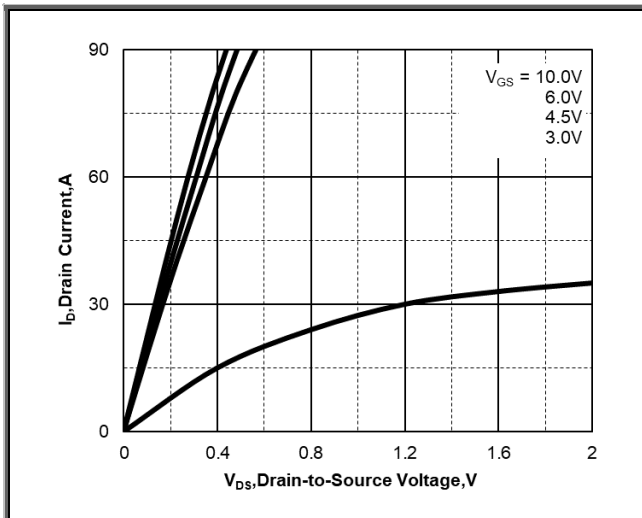


Fig 1: Typical Output Characteristics

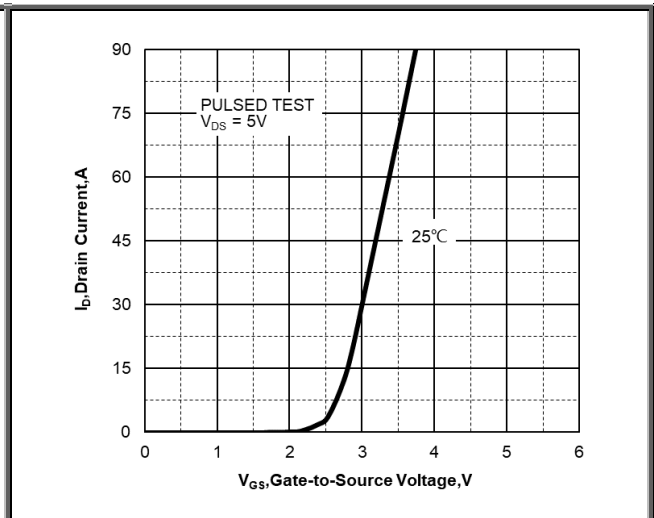


Fig 2: Typical Transfer Characteristics

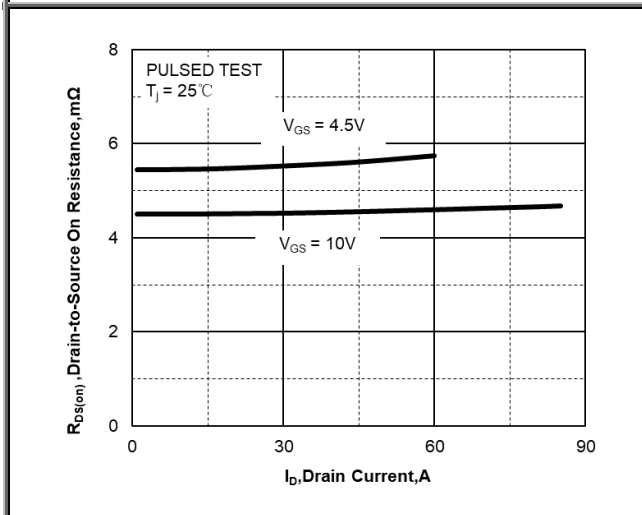


Fig 3: On-Resistance VS. Drain Current

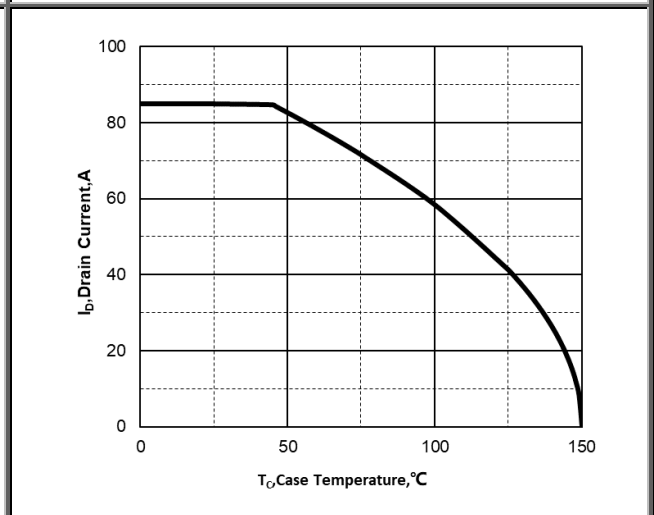


Fig 4: Maximum Continuous Drain Current VS. Case Temperature

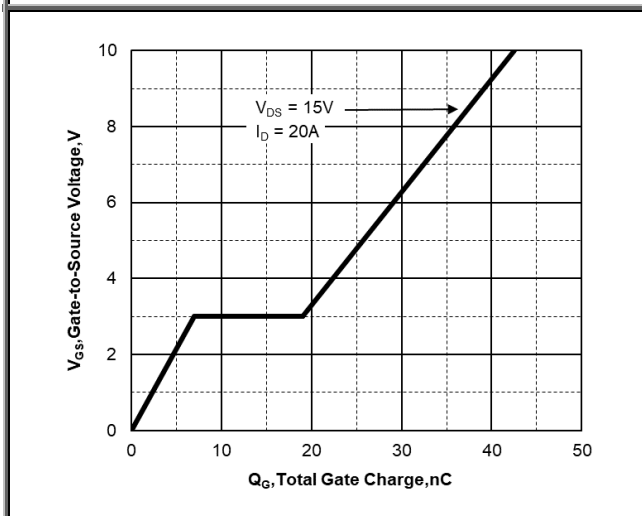


Fig 5: Gate Charge Characteristics

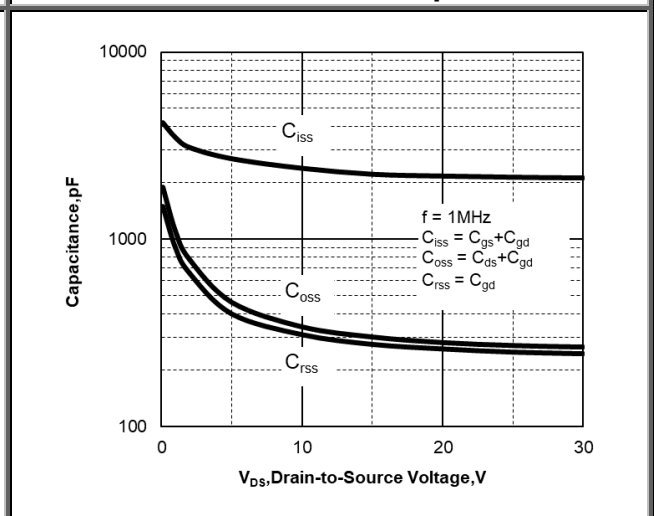


Fig 6: Capacitance Characteristics

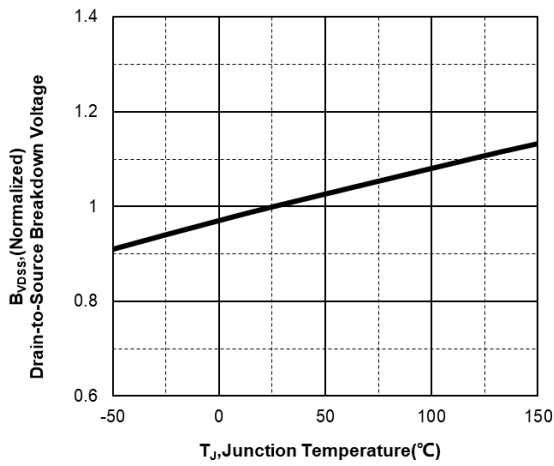


Fig 7: Normalized Breakdown Voltage VS. Junction Temperature

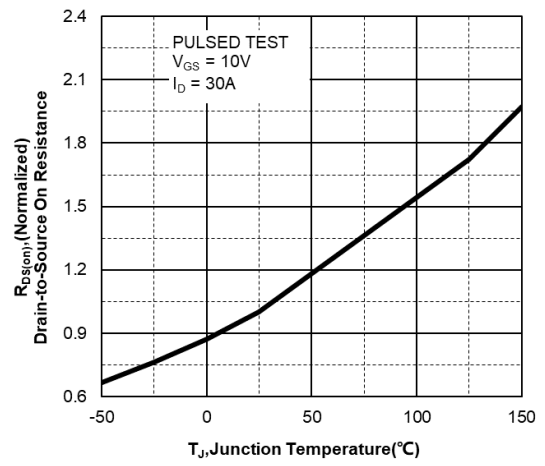


Fig 8: Normalized on Resistance VS. Junction Temperature

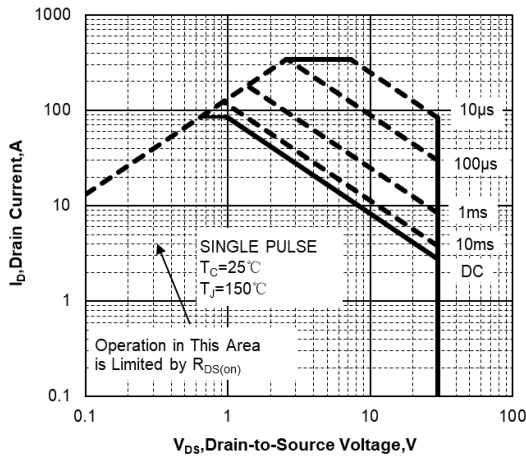


Fig 9: Maximum Safe Operating Area

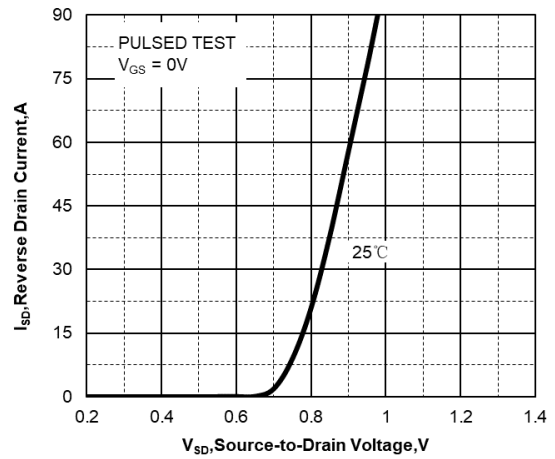


Fig 10: Body Diode Forward Characteristics

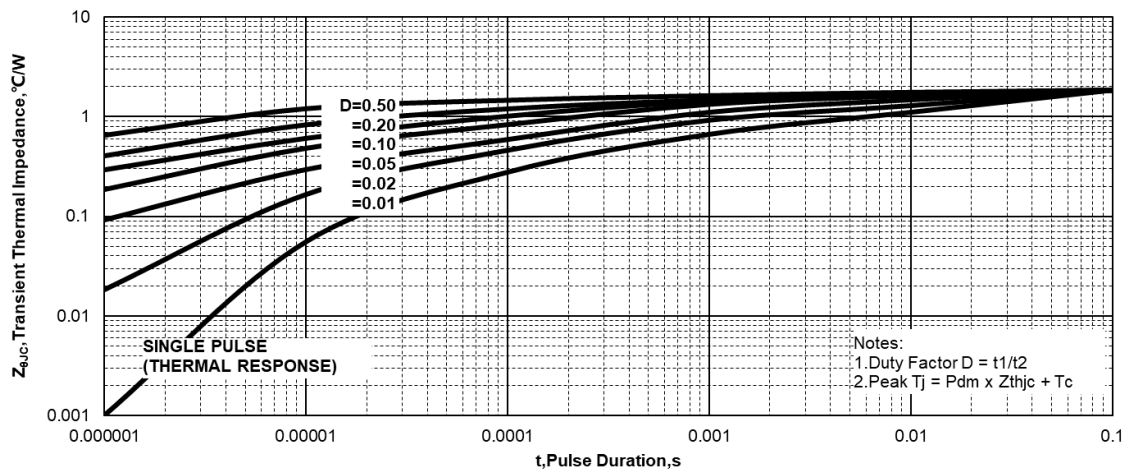
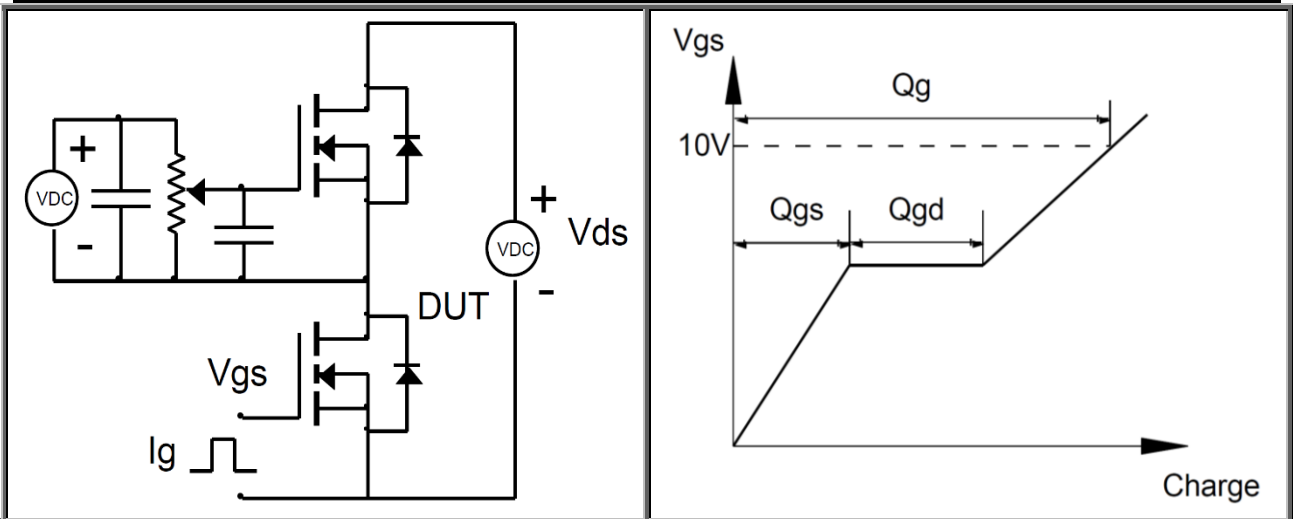
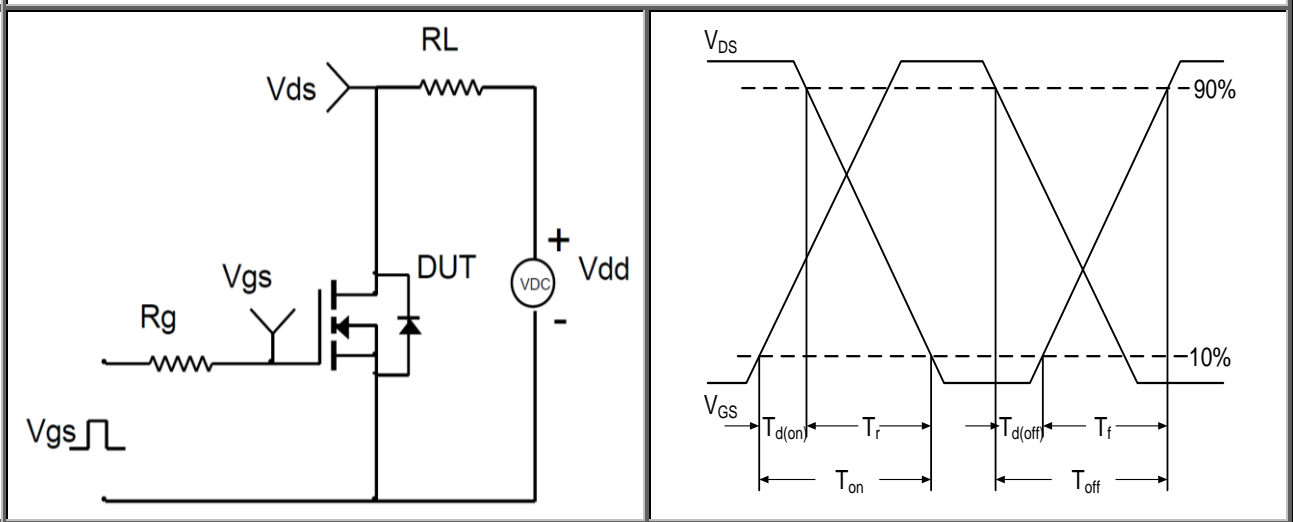


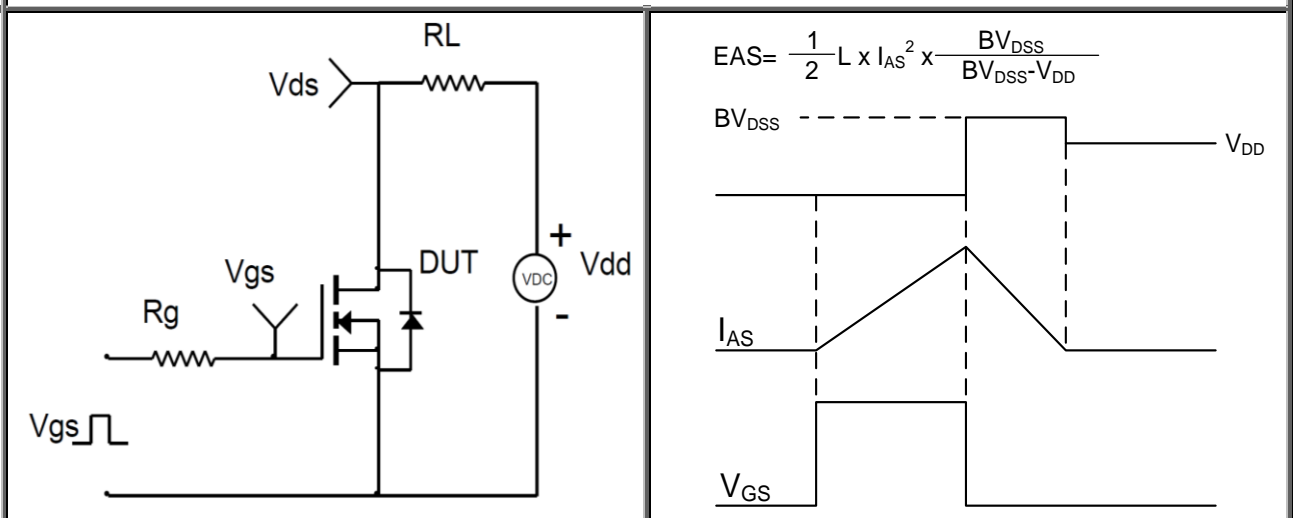
Fig.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Fig 12: Gate Charge Test Circuit and Waveforms**

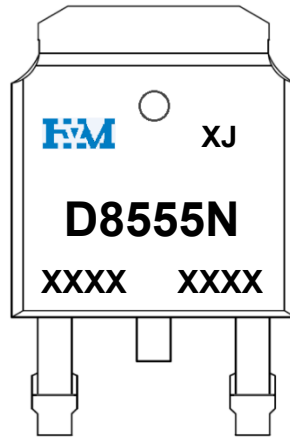


**Fig 13: Resistive Switching Test Circuit and Waveforms**



**Fig 14: Unclamped Inductive Switching Test Circuit and Waveforms**

## Marking Information



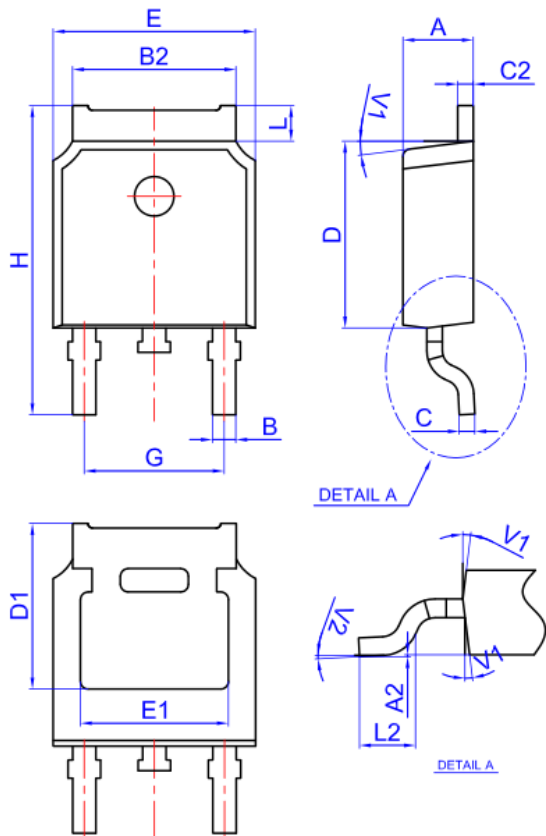
1st line: HM Logo (left) Coding (right) Changed with Machine Table

2nd line: Device Package and Part Number and Channel and Version

3rd line: Lot number And Date code (XXXX XXXX)

- ① XXXX: Wafer Lot Number Code Changed with Lot Number
- ② XXXX: Date code changed with Date Number, Factory Number

## TO-252 Dimension



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°



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